

Sample &

Buv



#### ISO3086T

Reference

Design

SLLSE27D - JANUARY 2011 - REVISED OCTOBER 2015

# ISO3086T Isolated 5-V RS-485 Transceiver With Integrated Transformer Driver

Technical

Documents

## 1 Features

- Meets or Exceeds TIA/EIA-485-A
- Signaling Rate up to 20 Mbps
- 1/8 Unit Load Up to 256 Nodes on a Bus
- Thermal Shutdown Protection
- Typical Efficiency > 60% (I<sub>LOAD</sub> = 100 mA) see SLUU469
- Low Bus Capacitance 7 pF (Typ)
- 50-kV/µs Typical Transient Immunity
- Fail-safe Receiver for Bus Open, Short, Idle
- Logic Inputs are 5-V Tolerant
- Bus-Pin ESD Protection
  - 11-kV HBM Between Bus-Pins and GND2
  - 6-kV HBM Between Bus-Pins and GND1
- · Safety and Regulatory Approvals
  - 4242 V<sub>PK</sub> Basic Insulation per DIN V VDE V 0884-10 and DIN EN 61010-1
  - 2500  $V_{RMS}$  Isolation for 1 minute per UL 1577
  - CSA Component Acceptance Notice 5A, IEC 60950-1 and IEC 61010-1 Standards

## 2 Applications

- Isolated RS-485/RS-422 Interfaces
- Factory Automation
- Motor/Motion Control
- HVAC and Building Automation Networks
- Networked Security Stations

## 3 Description

Tools &

Software

The ISO3086T is an isolated differential line transceiver with integrated oscillator outputs that provide the primary voltage for an isolation transformer. The device is a full-duplex differential line transceiver for RS-485 and RS-422 applications that can easily be configured for half-duplex operation by connecting pin 11 to pin 14, and pin 12 to pin 13.

Support &

Community

These devices are ideal for long transmission lines since the ground loop is broken to allow for a much larger common-mode voltage range. The symmetrical isolation barrier of the device is tested to provide 4242  $V_{PK}$  of isolation for 1 minute per VDE between the bus-line transceiver and the logic-level interface.

Any cabled I/O can be subjected to electrical noise transients from various sources. These noise transients can cause damage to the transceiver and/or near-by sensitive circuitry if they are of sufficient magnitude and duration. These isolated devices can significantly increase protection and reduce the risk of damage to expensive control circuits.

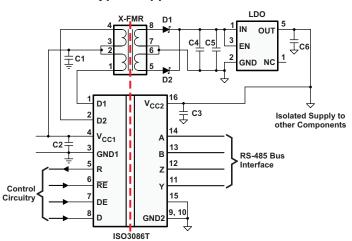
The ISO3086T is specified for use from  $-40^{\circ}$ C to  $85^{\circ}$ C.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
ISO3086T	SOIC (16)	10.30 mm × 7.50 mm

(1) For all available packages, see the orderable addendum at the end of the datasheet.

#### **Typical Application Circuit**



TEXAS INSTRUMENTS

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## **4** Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision C (July 2011) to Revision D	Page
Added Feature Item "Meets or Exceeds TIA/EIA-485"	1
VDE standard changed to DIN V VDE V 0884-10 (VDE V 0884-10):2006-12	1
Added Pin Configuration and Functions section, ESD Ratings table, Feature Description section, Device Fur Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, L and Documentation Support section, and Mechanical, Packaging, and Orderable Information section	Device
Changes from Revision B (July 2011) to Revision C	Page
Added Note 1 to the TRANSFORMER DRIVER CHARACTERISTICS table	5
<ul> <li>Changed the TRANSFORMER DRIVER CHARACTERISTICS table - f<sub>St</sub> Test Conditions From: .V<sub>CC1</sub> = 9V T = 2.4 and Changed the TYP value From: 230 To: 350 kHz.</li> </ul>	
Changes from Revision A (March 2011) to Revision B	Page
<ul> <li>Deleted the MIN and MAX values from rows, t<sub>r_d</sub>, t<sub>r_D</sub>, and t<sub>BBM</sub> of the TRANSFORMER DRIVER CHARACTERISTICS table</li> </ul>	6
Changes from Original (January 2011) to Revision A	Page
Changed the Features and Description	1
Changed the data sheet From: Preview To: Production	1
Added Figure 34 Typical Application Circuit	3



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## 5 Pin Configuration and Functions

DW Package 16-Pin SOIC Top View							
D1 🗹	1 ●	16 🔟 V <sub>CC2</sub>					
D2 🛙	2	15 🔟 GND2					
GND1	3	14 🖽 A					
V <sub>CC1</sub> II	4	13 🛄 B					
RU	5	12 🛄 Z					
RE 🛙	6	11 🖽 Y					
DE	7	10 🔟 NC					
DI	8	9 🔟 GND2					

#### **Pin Functions**

	PIN I/O		DESCRIPTION		
NAME	NO.	1/0	DESCRIPTION		
А	14	I	Non-inverting Receiver Input		
В	13	I	Inverting Receiver Input		
D1	1	0	Transformer Driver Terminal 1, Open Drain Output		
D2	2	0	Transformer Driver Terminal 2, Open Drain Output		
D	8	I	Driver Input		
DE	7	I	river Enable Input		
GND1	3	-	ogic-side Ground		
GND2	9, 15	-	Bus-side Ground. Both pins are internally connected.		
NC	10	-	No Connect. This pin is not connected to any internal circuitry.		
R	5	0	Receiver Output		
RE	6	I	Receiver Enable Input. This pin has complementary logic.		
V <sub>CC1</sub>	4	-	Logic-side Power Supply		
V <sub>CC2</sub>	16	-	Bus-side Power Supply		
Y	11	0	Non-inverting Driver Output		
Z	12	0	Inverting Driver Output		

## **6** Specifications

### 6.1 Absolute Maximum Ratings

See  $^{(1)}$ 

		MIN	MAX	UNIT
V <sub>CC1</sub> , V <sub>CC2</sub>	Input supply voltage <sup>(2)</sup>	-0.3	6	V
$V_A, V_B, V_Y, V_Z$	Voltage at any bus I/O terminal (A, B, Y, Z)	-9	14	V
$V_{D1}, V_{D2}$	Voltage at D1, D2		14	V
V <sub>(TRANS)</sub>	Voltage input, transient pulse through $100\Omega$ , see Figure 27 (A, B,Y, Z)	-50	50	V
VI	Voltage input at D, DE or RE terminal	-0.5	7	V
lo	Receiver output current	-10	10	mA
I <sub>D1</sub> , I <sub>D2</sub>	Transformer Driver Output Current		450	mA
TJ	Maximum junction temperature		170	°C
T <sub>STG</sub>	Storage temperature	-65	150	°C

Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
 All voltage values except differential I/O bus voltages are with respect to network ground terminal and are peak voltage values.

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## 6.2 ESD Ratings

				VALUE	UNIT
Electrostatic V <sub>(ESD)</sub> discharge			Bus pins and GND1	±6000	
	Human body model (HBM), per ANSI/ESDA/JEDEC JS-	Bus pins and GND2	±11000		
		All pins	±4000	V	
	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>		±1500		
		Machine model (MM), ANSI/ESDS5.2-1996		±200	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

## 6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V		3.3 V Operation	3	3.3	3.6	V
V <sub>CC1</sub>	Logic-side supply voltage	5 V Operation	4.5	5	5.5	v
V <sub>CC2</sub>	Bus-side supply voltage		4.5	5	5.5	V
$V_{I} \text{ or } V_{IC}$	Voltage at any bus terminal (separately or	common-mode)	-7		12	V
V <sub>IH</sub>	High-level input voltage	RE	2		V <sub>CC1</sub>	V
		D, DE	0.7 V <sub>CC1</sub>			V
V <sub>IL</sub>	Low-level input voltage	RE	0		0.8	V
		D, DE			0.3 V <sub>CC1</sub>	
M	Differential input valtage	A with respect to B	-12		12	12
V <sub>ID</sub>	Differential input voltage	Dynamic	See	e Figure 16		V
RL	Differential load resistance		54	60		Ω
	Output Output	Driver	-60		60	
I <sub>O</sub>	Output Current	Receiver	-8		8	mA
T <sub>A</sub>	Ambient temperature		-40		85	°C
TJ	Operating junction temperature		-40		150	°C
1 / t <sub>UI</sub>	Signaling Rate				20	Mbps

### 6.4 Thermal Information

	THERMAL METRIC <sup>(1)</sup>	DW (SOIC)	UNIT
		16 PINS	
$R_{\thetaJA}$	Junction-to-ambient thermal resistance	80.5	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	43.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49.7	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	13.8	°C/W
Ψ <sub>JB</sub>	Junction-to-board characterization parameter	41.4	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

## 6.5 Power Rating

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	VALUE	UNIT
P <sub>D</sub>	Maximum device power dissipation	$\label{eq:VCC1} \begin{array}{l} V_{CC1} = V_{CC2} = 5.5V, \ T_J = 150^\circ C, \ R_L = 54\Omega, \\ C_L = 50 pF \ (Driver), \ C_L = 15 pF \ (Receiver), \\ Input a 10 \ MHz \ 50\% \ duty \ cycle \ square \ wave \\ to \ Driver \ and \ Receiver \end{array}$	490	mW



## 6.6 Electrical Characteristics: Driver

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
		I <sub>O</sub> = 0 mA, no load		3	4.3	V <sub>CC2</sub>	
	Difference that has done to see the second second to do	$R_L = 54 \Omega$ (RS-485), See Figure	e 17	1.5	2.3		V
V <sub>OD</sub>	Differential output voltage magnitude	$R_L = 100 \ \Omega \ (RS-422), See Figu$	re 17	2	2.3		v
		V <sub>test</sub> from -7 V to +12 V, SeeFig	gure 18	1.5			
$\Delta  V_{OD} $	Change in magnitude of the differential output voltage	See Figure 17 and Figure 18		-0.2	0	0.2	V
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage			1	2.6	3	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage	Figure 19		-0.1		0.1	V
V <sub>OC(pp)</sub>	Peak-to-peak common-mode output voltage	See Figure 19			0.5		V
I <sub>I</sub>	Input current	D, DE, V <sub>I</sub> at 0 V or V <sub>CC1</sub>		-10		10	μA
	High-impedance state output current, Y or Z	$V_{Y}$ or $V_{Z}$ = 12 V, $V_{CC2}$ = 0 V or 5 V, DE = 0 V	Other bus pin			1	
I <sub>OZ</sub>	pin	$V_Y \text{ or } V_Z = -7 \text{ V},$ $V_{CC2} = 0 \text{ V or } 5 \text{ V}, \text{ DE} = 0 \text{ V}$	at 0 V	-1			μA
$I_{OS}^{(1)}$	Short-circuit output current	$-7 \text{ V} \le \text{V}_{\text{Y}} \text{ or } \text{V}_{\text{Z}} \le 12 \text{ V}$	Other bus pin at 0 V	-250		250	mA

(1) This device has thermal shutdown and output current limiting features to protect in short-circuit fault condition.

### 6.7 Electrical Characteristics: Receiver

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIO	ONS	MIN	TYP	MAX	UNIT
V <sub>IT(+)</sub>	Positive-going input threshold voltage	$I_0 = -8 \text{ mA}$			-85	-10	mV
V <sub>IT(-)</sub>	Negative-going input threshold voltage	$I_0 = 8 \text{ mA}$		-200	-115		mV
V <sub>hys</sub>	Hysteresis voltage (V <sub>IT+</sub> – V <sub>IT–</sub> )				30		mV
V		$V_{ID} = 200 \text{ mV}, I_O = -8 \text{ mA},$	$V_{CC1} = 3.3 V$	V <sub>CC1</sub> -0.4	3.1		V
V <sub>OH</sub>	High-level output voltage	See Figure 23	$V_{CC1} = 5 V$	4	4.8		v
V	Low lovel output veltage	V <sub>ID</sub> = 200 mV, I <sub>O</sub> = 8 mA,	$V_{CC1} = 3.3 V$		0.15	0.4	V
V <sub>OL</sub>	Low-level output voltage	See Figure 23	See Figure 23 $V_{CC1} = 5 V$		0.15	0.4	v
I <sub>O(Z)</sub>	High-impedance state output current	$V_{O} = 0 \text{ or } V_{CC1}, \overline{RE} = V_{CC1}$		-1		1	μA
		$V_A$ or $V_B = 12 V$			40	100	
		$V_A \text{ or } V_B = 12 \text{ V}, V_{CC2} = 0$	Other input		60	130	
I <sub>A</sub> , I <sub>B</sub>	Bus input current	$V_A$ or $V_B = -7 V$	at 0 V	-100	-40		μA
		$V_A$ or $V_B = -7$ V, $V_{CC2} = 0$		-100	-30		
I <sub>IH</sub>	High-level input current, RE	V <sub>IH</sub> = 2. V		-10		10	A
$I_{IL}$	Low-level input current, RE	V <sub>IL</sub> = 0.8 V		-10		10	μA
R <sub>ID</sub>	Differential input resistance	A, B		96			kΩ
CID	Differential input capacitance	V <sub>I</sub> = 0.4 sin (4E6πt) + 0.5 V			7		pF

### 6.8 Transformer Driver Characteristics

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
£	Opsillator fraguence	$V_{CC1}$ = 5 V ± 10%, D1 and D2 connected to transformer	350	450	610	kHz
tosc	Oscillator frequency	$V_{CC1}$ = 3.3 V $\pm$ 10%, D1 and D2 connected to transformer	300	400	550	KHZ
R <sub>ON</sub>	Switch on resistance	D1 and D2 connected to $50\Omega$ pull-up resistors		1	2.5	Ω

## **Transformer Driver Characteristics (continued)**

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
	D4 D2 sutsut riss time	$V_{CC1} = 5 V \pm 10\%$ , see Figure 29, <sup>(1)</sup>		80				
t <sub>r_D</sub>	D1, D2 output rise time	$V_{CC1} = 3.3 \text{ V} \pm 10\%$ , see Figure 29, <sup>(1)</sup>		70		ns		
	D1, D2 output fall time	$V_{CC1} = 5 V \pm 10\%$ , see Figure 29, <sup>(1)</sup>		55		~~		
t <sub>f_D</sub>		$V_{CC1} = 3.3 \text{ V} \pm 10\%$ , see Figure 29, <sup>(1)</sup>		80		ns		
f <sub>St</sub>	Startup frequency	V <sub>CC1</sub> = 2.4 V, D1 and D2 connected to transformer		350		kHz		
	Break before make time delay	$V_{CC1} = 5 V \pm 10\%$ , see Figure 29, <sup>(1)</sup>		38		~~		
t <sub>BBM</sub>		$V_{CC1} = 3.3 \text{ V} \pm 10\%$ , see Figure 29, <sup>(1)</sup>		140		ns		

(1) D1 and D2 connected to  $50\Omega$  pull-up resistors

## 6.9 Supply Current and Common-Mode Transient Immunity

over recommended operating conditions (unless otherwise noted)

	PARAMETER TEST CONDITIONS		MIN	TYP	MAX	UNIT	
I <sub>CC1</sub> <sup>(1)</sup>	Logic-side quiescent	DE and $\overline{RE} = 0$ V or V <sub>CC1</sub> (Driver and Receiver	$V_{CC1} = 3.3 \text{ V} \pm 10\%$		5	8	m۸
ICC1 \	supply current	Enabled or Disabled), $D = 0$ V or V <sub>CC1</sub> , No load	$V_{CC1} = 5 V \pm 10\%$		7	12	mA
ı (1)	Bus-side quiescent	$\overline{RE} = 0 \text{ V or V}_{CC1}, DE = 0 \text{ V (driver disabled), No}$	load		10	15	~ ^
ICC2	$\frac{1}{RE} = 0 \text{ V or } V_{CC1},  \text{DE} = 0 \text{ V or } V_{CC1},  \text{DE} = 0 \text{ V or } V_{CC1},  \text{No Load}$			10	15	mA	
СМТІ	Common-mode transient immunity	See Figure 28, $V_I = V_{CC1}$ or 0 V			50		kV/µs

I<sub>CC1</sub> and I<sub>CC2</sub> are measured when device is connected to external power supplies, V<sub>CC1</sub> and V<sub>CC2</sub>. In this case, D1 and D2 are open and disconnected from external transformer.

## 6.10 Switching Characteristics: Driver

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH},t_{PHL}$	Propagation delay			25	45	
PWD <sup>(1)</sup>	Pulse width distortion ( t <sub>PHL</sub> – t <sub>PLH</sub>  )	See Figure 20		1	7.5	ns
t <sub>r</sub> , t <sub>f</sub>	Differential output signal rise time and fall time			7	15	
t <sub>PZH</sub> , t <sub>PHZ</sub>	Propagation delay, high-impedance-to-high-level output, Propagation delay, high-level-to-high-impedance output	See Figure 21 DE at 0 V		25	55	ns
t <sub>PLZ</sub> , t <sub>PZL</sub>	Propagation delay, low-level to high-impedance output, Propagation delay, high-impedance to low-level output	See Figure 22, DE at 0 V		25	55	ns

(1) Also known as pulse skew

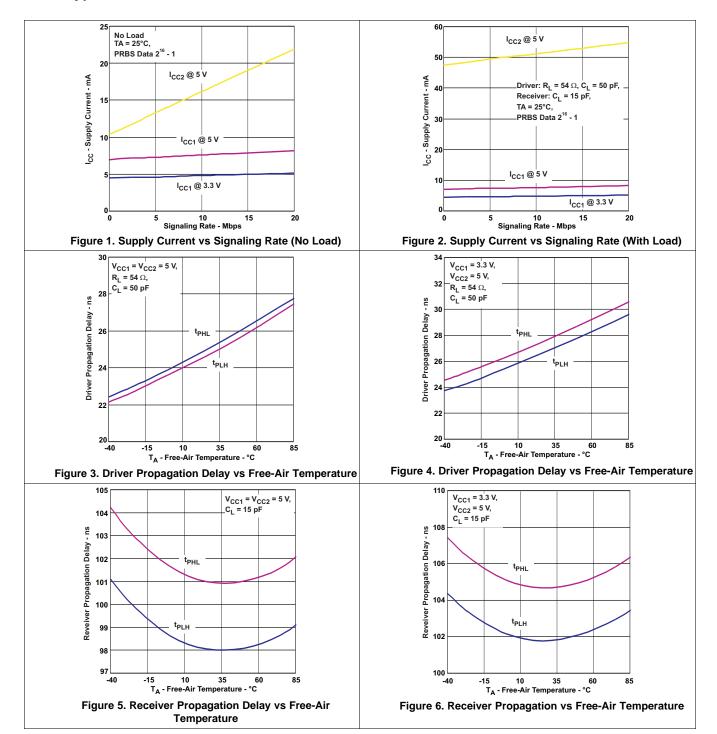
## 6.11 Switching Characteristics: Receiver

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
$t_{PLH},  t_{PHL}$	Propagation delay		103	125	
t <sub>sk(p)</sub>	Pulse skew ( t <sub>PHL</sub> - t <sub>PLH</sub>  )	See Figure 24	3	15	ns
t <sub>r</sub> , t <sub>r</sub>	Output signal rise and fall time		1		
t <sub>PHZ</sub> , t <sub>PZH</sub>	Propagation delay, high-level to high-impedance output Propagation delay, high-impedance to high-level output	See Figure 25, DE at 0 V	11	22	2
t <sub>PLZ</sub> , t <sub>PZL</sub>	Propagation delay, low-level to high-impedance output Propagation delay, high-impedance to low-level output	See Figure 26, DE at 0 V	11	22	ns

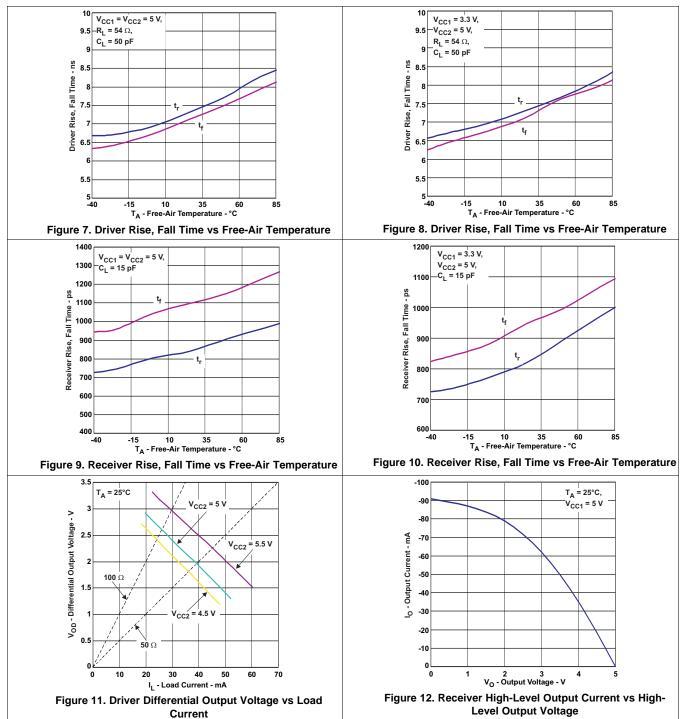


## 6.12 Typical Characteristics



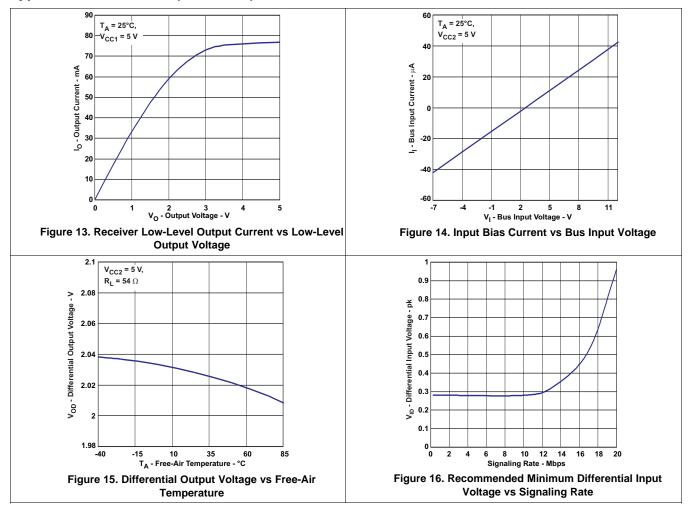


### **Typical Characteristics (continued)**





### **Typical Characteristics (continued)**





## 7 Parameter Measurement Information

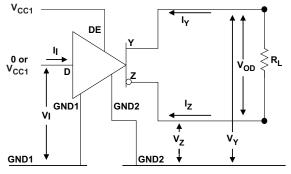
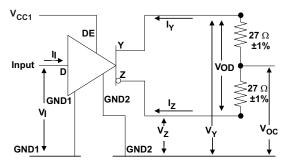


Figure 17. Driver V<sub>OD</sub> Test and Current Definitions



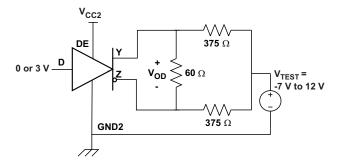


Figure 18. Driver V<sub>OD</sub> With Common-Mode Loading Test Circuit

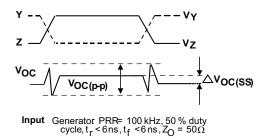


Figure 19. Test Circuit and Waveform Definitions For The Driver Common-Mode Output Voltage

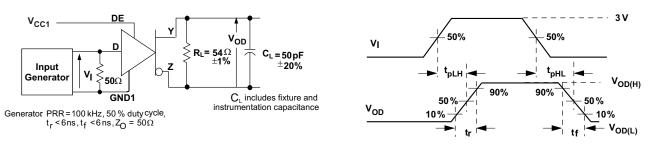
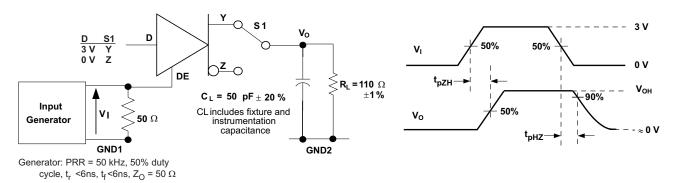


Figure 20. Driver Switching Test Circuit and Voltage Waveforms







### Parameter Measurement Information (continued)

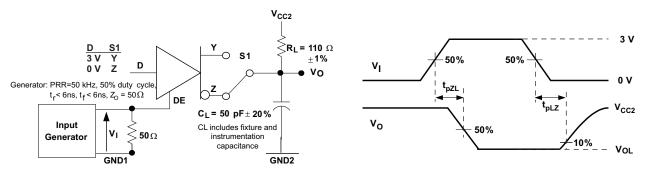
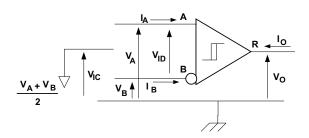


Figure 22. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveform





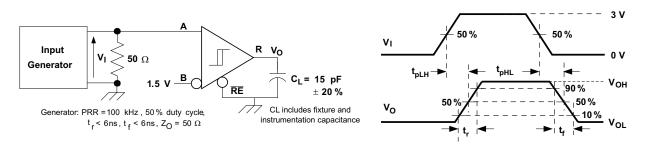
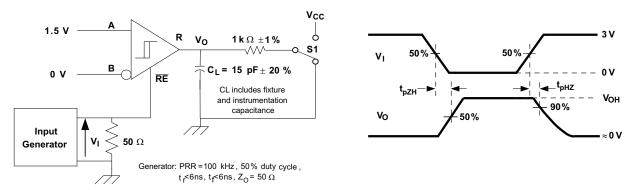


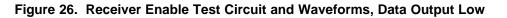
Figure 24. Receiver Switching Test Circuit and Waveforms





Vcc А 0 V R vo 1 k $\Omega \pm 1$ % **3** V  $\sim$ S1 50% 50% ٧I в  $\stackrel{\perp}{\uparrow}$  C<sub>L</sub> = 15 pF  $\pm$  20 % 1.5 V RE 0 V CL includes fixture and instrumentation capacitance t<sub>pZL</sub>—► t<sub>pLZ</sub> v<sub>cc</sub> Input **50** Ω Generator Vı 50% vo 10% Generator : PRR = 100 kHz, 50% duty cycle, VOL  $t_r$  < 6ns,  $t_f$  < 6ns,  $Z_O$  = 50  $\Omega$ 

**Parameter Measurement Information (continued)** 



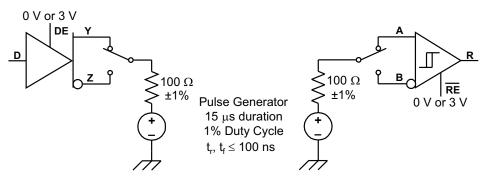
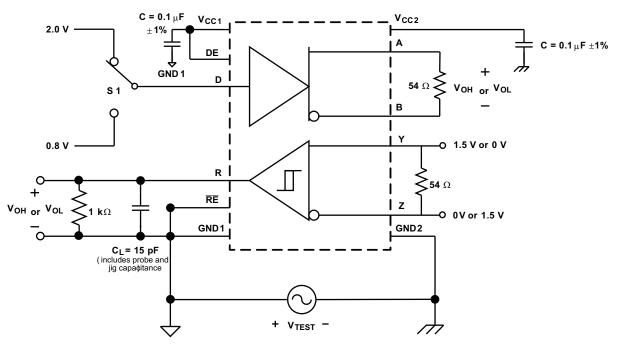


Figure 27. Transient Over-Voltage Test Circuit





**EXAS** 



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## Parameter Measurement Information (continued)

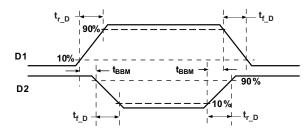


Figure 29. Transition Times and Break-Before-Make Time Delay for D1, D2 Outputs



## 8 Detailed Description

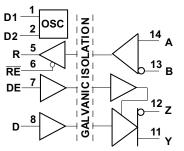
### 8.1 Overview

ISO3086T is an isolated full-duplex differential transceiver with integrated transformer driver. The integrated transformer driver supports elegant secondary power supply design. This device is rated to provide galvanic isolation up to 4242  $V_{PK}$  per VDE and 2500  $V_{RMS}$  per UL. It has active-high driver enable and active-low receiver enable to control the data flow. It is suitable for data transmission up to 20 Mbps.

When the driver enable pin, DE, is logic high, the differential outputs Y and Z follow the logic states at data input D. A logic high at D causes Y to turn high and Z to turn low. In this case the differential output voltage defined as  $V_{OD} = V_{(Y)} - V_{(Z)}$  is positive. When D is low, the output states reverse, Z turns high, Y becomes low, and  $V_{OD}$  is negative. When DE is low, both outputs turn high-impedance. In this condition the logic state at D is irrelevant. The DE pin has an internal pulldown resistor to ground, thus when left open the driver is disabled (high-impedance) by default. The D pin has an internal pullup resistor to V<sub>CC</sub>, thus, when left open while the driver is enabled, output Y turns high and Z turns low.

When the receiver enable pin,  $\overline{RE}$ , is logic low, the receiver is enabled. When the differential input voltage defined as  $V_{ID} = V_{(A)} - V_{(B)}$  is positive and higher than the positive input threshold,  $V_{IT+}$ , the receiver output, R, turns high. When  $V_{ID}$  is negative and lower than the negative input threshold,  $V_{IT-}$ , the receiver output, R, turns low. If  $V_{ID}$  is between  $V_{IT+}$  and  $V_{IT-}$  the output is indeterminate. When  $\overline{RE}$  is logic high or left open, the receiver output is high-impedance and the magnitude and polarity of  $V_{ID}$  are irrelevant. Internal biasing of the receiver inputs causes the output to go failsafe-high when the transceiver is disconnected from the bus (open-circuit), the bus lines are shorted (short-circuit), or the bus is not actively driven (idle bus).

#### 8.2 Functional Block Diagram



#### 8.3 Feature Description

### 8.3.1 Insulation and Safety Related Specifications for 16 DW Package

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance <sup>(1)</sup> )	Shortest terminal to terminal distance through air	8			mm
L(I02)	Minimum external tracking (Creepage <sup>(1)</sup> )	Shortest terminal to terminal distance across the package surface	8			mm
СТІ	Comparative Tracking Index (Tracking resistance)	DIN EN 60112 (VDE 0303-11); IEC 60112	400			V
DTI	Distance through the insulation	Minimum Internal Gap (Internal Clearance)	0.008			mm
R <sub>IO</sub>	Isolation resistance	Input to output, $V_{IO}$ = 500 V, all pins on each side of the barrier tied together creating a two-terminal device, $T_A$ = 25 °C		>10 <sup>12</sup>		Ω
C <sub>IO</sub>	Barrier capacitance Input to output	$V_{\text{IO}}$ = $V_{\text{CC}}/2$ + 0.4 sin (2πft), f = 1 MHz, $V_{\text{CC}}$ = 5 V		2		pF
CI	Input capacitance to ground	V <sub>I</sub> = 0.4 sin (2πft), f = 1 MHz		2		pF

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board do not reduce this distance. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

### 8.3.1.1 IEC 60664-1 Ratings Table

PARAMETER	TEST CONDITIONS	SPECIFICATION
Material group		II
Overvoltage category / Installation	Rated mains voltage ≤ 150 V <sub>RMS</sub>	I-IV
classification for basic insulation	Rated mains voltage ≤ 300 V <sub>RMS</sub>	1-111

### 8.3.1.2 DIN V VDE V 0884-10 Insulation Characteristics<sup>(1)</sup>

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	SPECIFICATION	UNIT
VIORM	Maximum working isolation voltage		566	V <sub>PK</sub>
		Method b1, $V_{PR} = V_{IORM} \times 1.875$ , 100% Production test with t = 1 s, Partial discharge < 5 pC	1062	V <sub>PK</sub>
V <sub>PR</sub>	Input to output test voltage	Method a, After environmental tests subgroup 1, $V_{PR} = V_{IORM} \times 1.6$ , t = 10 s, Partial discharge < 5pC	906	
		After Input/Output Safety Test Subgroup 2/3, $V_{PR} = V_{IORM} \times 1.2$ , t = 10 s, Partial discharge < 5 pC	680	
V <sub>IOTM</sub>	Maximum transient isolation voltage	t = 60 s (Qualification) t = 1 s (100% Production)	4242	V <sub>PK</sub>
V <sub>IOSM</sub>	Maximum surge isolation voltage	Tested per IEC 60065, 1.2/50 $\mu$ s waveform, V <sub>TEST</sub> = 1.3 x V <sub>IOSM</sub> = 4000 V <sub>PK</sub> (Qualification Test)	3077	V <sub>PK</sub>
R <sub>S</sub>	Isolation resistance	V <sub>IO</sub> = 500 V at T <sub>S</sub> = 150 °C	> 10 <sup>9</sup>	Ω
	Pollution degree		2	

(1) Climatic Classification 40/125/21

#### 8.3.1.3 Regulatory Information

VDE	CSA	UL
Certified according to DIN V VDE V 0884- 10(VDE V 0884-10):2006-12 and DIN EN 61010-1 (VDE 0411-1)	Approved according to CSA Component Acceptance Notice 5A, IEC 60959-1 and IEC 61010-1	Approved under UL 1577 Component Recognition Program
Basic Insulation Maximum Transient Isolation Voltage, 4242 $V_{PK}$ Maximum Surge Isolation Voltage, 3077 $V_{PK}$ Maximum Working Isolation Voltage, 566 $V_{PK}$	$\begin{array}{c} 3000 \ V_{RMS} \ \text{Isolation Rating}; \\ \text{Reinforced insulation per CSA 61010-1-04 and} \\ \text{IEC 61010-1 2nd Ed. 150} \ V_{RMS} \ \text{working voltage}; \\ \text{Basic insulation per CSA 61010-1-04 and IEC} \\ \text{61010-1 2nd Ed. 600} \ V_{RMS} \ \text{working voltage}; \\ \text{Basic insulation per CSA 60950-1-07 and IEC} \\ \text{60950-1 2nd Ed. 760} \ V_{RMS} \ \text{working voltage} \end{array}$	Single Protection, 2500 V <sub>RMS</sub> <sup>(1)</sup>
Certificate Number: 40016131	Master Contract Number: 220991	File Number: E181974

(1) Production tested  $\ge$  3000 V<sub>RMS</sub> for 1 second in accordance with UL 1577.

#### 8.3.1.4 Safety Limiting Values

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the IO can allow low resistance to ground or the supply. Without current limiting, sufficient power is dissipated to overheat the die and damage the isolation barrier—potentially leading to secondary system failures.

	PARAMETER TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{S}$	Safety input, output, or supply current	DW-16	$\theta_{JA} = 80.5^{\circ}C/W, V_{I} = 5.5 V, T_{J} = 170^{\circ}C, T_{A} = 25^{\circ}C$			327	mA
$T_S$	Maximum safety temperature	DVV-16				150	°C

The safety-limiting constraint is the maximum junction temperature specified for the device. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the Thermal Characteristics table is that of a device installed on a High-K Test Board for Leaded Surface Mount Packages. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

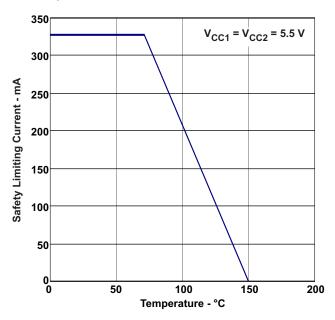


Figure 30. Thermal Derating Curve per VDE

#### 8.4 Device Functional Modes

Table 1 and Table 2 are the function tables for the ISO3086T driver and receiver.

INPUT	ENABLE	OUTPUTS		
(D)	(DE)	Y	Z	
Н	Н	Н	L	
L	Н	L	Н	
Х	L	hi-Z	hi-Z	
Х	OPEN	hi-Z	hi-Z	
OPEN	Н	Н	L	

### Table 1. Driver Function Table<sup>(1)</sup>

(1) H = High Level, L= Low Level, X = Don't Care, hi-Z = High Impedance (off)

DIFFERENTIAL INPUT $V_{ID} = (V_A - V_B)$	ENABLE (RE)	OUTPUT (R)		
-0.01 V ≤ V <sub>ID</sub>	L	Н		
-0.2 V < V <sub>ID</sub> -0.01 V	L	?		
$V_{ID} \le -0.2 V$	L	L		
X	Н	hi-Z		
X	OPEN	hi-Z		
Open circuit	L	Н		
Short Circuit	L	Н		
Idle (terminated) bus	L	Н		

(1) H = High Level, L= Low Level, X = Don't Care, hi-Z = High Impedance (Off), ? = Indeterminate

ISO3086T

SLLSE27D – JANUARY 2011 – REVISED OCTOBER 2015



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## 8.4.1 Device I/O Schematics

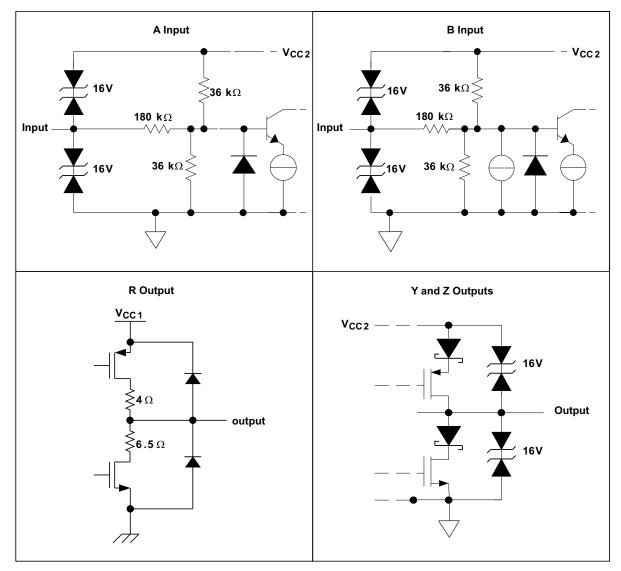


Figure 31. Equivalent Circuit Schematics



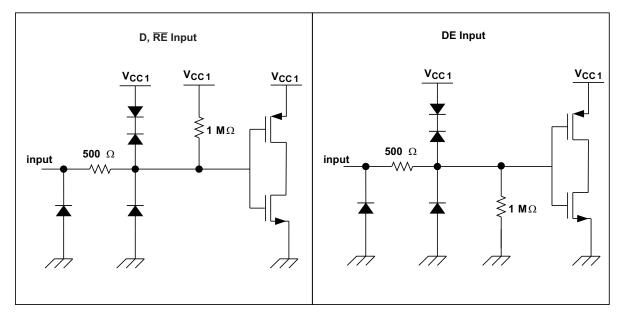


Figure 32. Equivalent Circuit Schematics



## 9 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 9.1 Application Information

The ISO308T consists of an RS-485 transceiver commonly used for asynchronous data transmissions. Fullduplex implementation requires two signal pairs (four wires), and allows each node to transmit data on one pair while simultaneously receiving data on the other pair. To eliminate line reflections, each cable end is terminated with a termination resistor, R(T), whose value matches the characteristic impedance, Z0, of the cable. This method, known as parallel termination, allows for higher data rates over longer cable length.

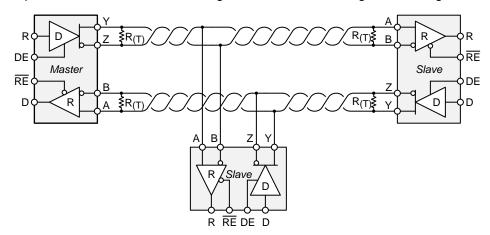


Figure 33. Half-Duplex Transceiver Configurations

### 9.2 Typical Application

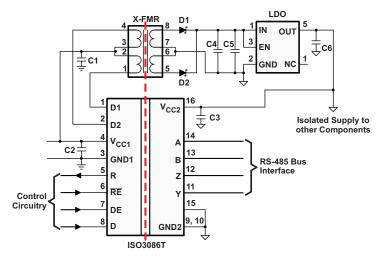


Figure 34. Typical Application Circuit



#### **Typical Application (continued)**

#### 9.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

PARAMETER	VALUE
Pullup and Pulldown Resistors	1 kΩ to 10 kΩ
Decoupling Capacitors	100 nF

#### **Table 3. Design Parameters**

#### 9.2.2 Detailed Design Procedure

#### 9.2.2.1 Transient Voltages

Isolation of a circuit insulates it from other circuits and earth so that noise develops across the insulation rather than circuit components. The most common noise threat to data-line circuits is voltage surges or electrical fast transients that occur after installation and the transient ratings of the ISO3086T are sufficient for all but the most severe installations. However, some equipment manufacturers use their ESD generators to test transient susceptibility of their equipment and can easily exceed insulation ratings. ESD generators simulate static discharges that may occur during device or equipment handling with low-energy but very high voltage transients.

Figure 35 models the ISO3086T bus IO connected to a noise generator.  $C_{IN}$  and  $R_{IN}$  is the device and any other stray or added capacitance or resistance across the A or B pin to GND2,  $C_{ISO}$  and  $R_{ISO}$  is the capacitance and resistance between GND1 and GND2 of the ISO3086T plus those of any other insulation (transformer, etc.), and we assume stray inductance negligible. From this model, the voltage at the isolated bus return is shown in Equation 1 and will always be less than 16 V from  $V_N$ .

$$v_{GND2} = v_N \frac{Z_{ISO}}{Z_{ISO} + Z_{IN}}$$
(1)

If the ISO3086T are tested as a stand-alone device,  $R_{IN} = 6 \times 10^4 \Omega$ ,  $C_{IN} = 16 \times 10^{-12}$  F,  $R_{ISO} = 10^9 \Omega$  and  $C_{ISO} = 10^{-12}$  F.

In Figure 35 the resistor ratio determines the voltage ratio at low frequency and it is the inverse capacitance ratio at high frequency. In the stand-alone case and for low frequency, use Equation 2, or essentially all of noise appears across the barrier.

$$\frac{v_{GND2}}{v_N} = \frac{R_{ISO}}{R_{ISO} + R_{IN}} = \frac{10^9}{10^9 + 6 \times 10^4}$$
(2)

At very high frequency, Equation 3 is true, and 94% of  $V_N$  appears across the barrier.

$$\frac{v_{GND2}}{v_N} = \frac{\overline{C_{ISO}}}{\frac{1}{C_{ISO}} + \frac{1}{C_{IN}}} = \frac{1}{1 + \frac{C_{ISO}}{C_{IN}}} = \frac{1}{1 + \frac{1}{16}} = 0.94$$
(3)

As long as  $R_{ISO}$  is greater than  $R_{IN}$  and  $C_{ISO}$  is less than  $C_{IN}$ , most of transient noise appears across the isolation barrier, as it should.

TI recommends not testing equipment transient susceptibility with ESD generators or consider product claims of ESD ratings above the barrier transient ratings of an isolated interface. ESD is best managed through recessing or covering connector pins in a conductive connector shell and installer training.



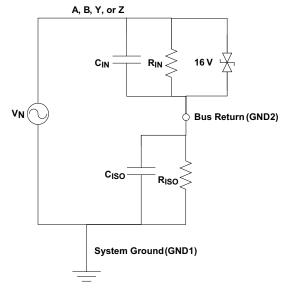


Figure 35. Noise Model

## 9.2.3 Application Curve

At maximum working voltage, ISO3086T isolation barrier has more than 28 years of life.

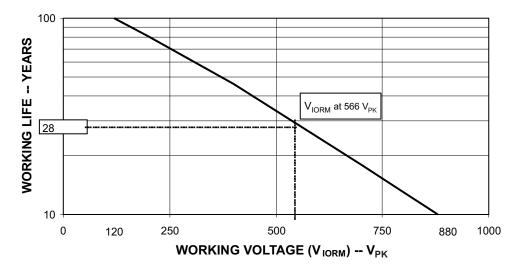


Figure 36. Time-Dependent Dielectric Breakdown Test Results



## **10 Power Supply Recommendations**

To ensure reliable operation at all data rates and supply voltages, TI recommends a  $0.1-\mu$ F bypass capacitor at input and output supply pins (V<sub>CC1</sub> and V<sub>CC2</sub>). The capacitors should be placed as close to the supply pins as possible. This device is used in applications where only a single primary-side power supply is available. Isolated power can be generated for the secondary-side with the help of integrated transformer driver.

## 11 Layout

## 11.1 Layout Guidelines

ON-chip IEC-ESD protection is good for laboratory and portable equipment but never sufficient for EFT and surge transients occurring in industrial environments. Therefore, robust and reliable bus node design requires the use of external transient protection devices. Because ESD and EFT transients have a wide frequency bandwidth from approximately 3-MHz to 3-GHz, high-frequency layout techniques must be applied during PCB design. A minimum of four layers is required to accomplish a low EMI PCB design (see Figure 37).

- Layer stacking should be in the following order (top-to-bottom): high-speed signal layer, ground plane, power plane, and low-frequency signal layer.
- Placing a solid ground plane next to the high-speed signal layer establishes controlled impedance for transmission line interconnects and provides an excellent low-inductance path for the return current flow.
- Placing the power plane next to the ground plane creates additional high-frequency bypass capacitance of approximately 100 pF/in<sup>2</sup>.
- Routing the slower speed control signals on the bottom layer allows for greater flexibility as these signal links usually have margin to tolerate discontinuities such as vias.
- Place the protection circuitry close to the bus connector to prevent noise transients from penetrating your board.
- Use V<sub>CC</sub> and ground planes to provide low-inductance. High-frequency currents might follow the path of least inductance and not necessarily the path of least resistance.
- Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
- Apply 0.1- $\mu$ F bypass capacitors as close as possible to the V<sub>CC</sub>-pins of transceiver, UART, and controller ICs on the board.
- Use at least two vias for V<sub>CC</sub> and ground connections of bypass capacitors and protection devices to minimize effective via-inductance.
- Use  $1-k\Omega$  to  $10-k\Omega$  pullup and pulldown resistors for enable lines to limit noise currents in these lines during transient events.
- Insert pulse-proof resistors into the A and B bus lines if the TVS clamping voltage is higher than the specified maximum voltage of the transceiver bus pins. These resistors limit the residual clamping current into the transceiver and prevent it from latching up.
- While pure TVS protection is sufficient for surge transients up to 1 kV, higher transients require metal-oxide varistors (MOVs) which reduce the transients to a few hundred volts of clamping voltage, and transient blocking units (TBUs) that limit transient current to less than 1 mA.
- Routing the high-speed traces on the top layer avoids the use of vias (and the introduction of their inductances) and allows for clean interconnects between the isolator and the transmitter and receiver circuits of the data link.

If an additional supply voltage plane or signal layer is needed, add a second power and ground plane system to the stack to keep it symmetrical. This makes the stack mechanically stable and prevents it from warping. Also the power and ground plane of each power system can be placed closer together, thus increasing the high-frequency bypass capacitance significantly.

#### NOTE

For detailed layout recommendations, see Application Note *Digital Isolator Design Guide*, SLLA284.

TEXAS INSTRUMENTS

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## 11.2 Layout Example

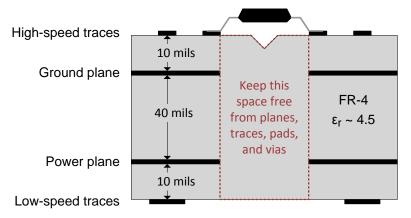


Figure 37. Recommended Layer Stack



## **12 Device and Documentation Support**

## **12.1** Documentation Support

#### 12.1.1 Related Documentation

For related documentation see the following:

- Isolated, Full-Duplex, 20-Mbps, 3.3-V to 5-V RS-485 Interface (SLUU469)
- Digital Isolator Design Guide (SLLA284)
- Isolation Glossary (SLLA353)

## 12.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E<sup>™</sup> Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support TI's Design Support** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 12.3 Trademarks

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### **12.4 Electrostatic Discharge Caution**



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### 12.5 Glossary

#### SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

### 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



10-Dec-2020

## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
ISO3086TDW	ACTIVE	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ISO3086T	Samples
ISO3086TDWR	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ISO3086T	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# PACKAGE OPTION ADDENDUM

10-Dec-2020

# PACKAGE MATERIALS INFORMATION

Texas Instruments

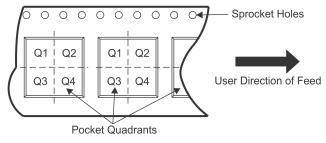
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## TAPE AND REEL INFORMATION





## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are n	ominal
-----------------------	--------

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO3086TDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1



# PACKAGE MATERIALS INFORMATION

5-Jan-2022



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO3086TDWR	SOIC	DW	16	2000	350.0	350.0	43.0



5-Jan-2022

## TUBE



#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
ISO3086TDW	DW	SOIC	16	40	506.98	12.7	4826	6.6

# **DW 16**

# **GENERIC PACKAGE VIEW**

## SOIC - 2.65 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

7.5 x 10.3, 1.27 mm pitch

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





# **DW0016B**



# **PACKAGE OUTLINE**

SOIC - 2.65 mm max height

SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- Per ASME Y14.5M.
   This drawing is subject to change without notice.
   This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.



# DW0016B

# **EXAMPLE BOARD LAYOUT**

## SOIC - 2.65 mm max height

SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# DW0016B

# **EXAMPLE STENCIL DESIGN**

# SOIC - 2.65 mm max height

SOIC



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



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